



Product Change Notification / JAON-04IGFH099

Date:

09-Feb-2021

Product Category:

Power MOSFET Drivers

PCN Type:

Manufacturing Change

Notification Subject:

CCB 4542 Initial Notice: Qualification of a new lead frame design for selected products available in 8L SOIC package using 8900NC die attach and gold (Au) bond wire material assembled at MMT assembly site.

Affected CPNs:

[JAON-04IGFH099_Affected_CPN_02092021.pdf](#)

[JAON-04IGFH099_Affected_CPN_02092021.csv](#)

Notification Text:

PCN Status: Initial notification

PCN Type: Manufacturing Change

Microchip Parts Affected: Please open one of the files found in the Affected CPNs section.

NOTE: For your convenience Microchip includes identical files in two formats (.pdf and .xls).

Description of Change: Qualification of a new lead frame design for selected products available in 8L SOIC package using 8900NC die attach and gold (Au) bond wire material assembled at MMT assembly site.

Pre Change:

Using lead frame without lead lock

Post Change:

Using lead frame with lead lock

Pre and Post Change Summary:

	Pre Change	Post Change
Assembly Site	Microchip Technology Thailand (Branch) / MMT	Microchip Technology Thailand (Branch) / MMT
Wire material	Au	Au
Die attach material	8900NC	8900NC
Molding compound material	G600V	G600V
Lead frame material	CDA194	CDA194
Lead Frame Lead Lock	No	Yes
	See attached pre and post change comparison	

Impacts to Data Sheet: None

Change Impact:None

Reason for Change:To improve productivity by qualifying new lead frame design.

Change Implementation Status:In Progress

Estimated Qualification Completion Date:March 2021

Note: Please be advised the qualification completion times may be extended because of unforeseen business conditions however implementation will not occur until after qualification has completed and a final PCN has been issued. The final PCN will include the qualification report and estimated first ship date. Also note that after the estimated first ship date guided in the final PCN customers may receive pre and post change parts.

Time Table Summary:

	February 2021				March 2021				
Workweek	06	07	08	09	10	11	12	13	14
Initial PCN Issue Date		X							
Qual Report Availability							X		
Final PCN Issue Date							X		

Method to Identify Change:

Traceability code

Qualification Plan:Please open the attachments included with this PCN labeled as PCN_#_Qual_Plan.

Revision History:February 9, 2021: Issued initial notification.

The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable products.

Attachments:

[PCN_JAON-04IGFH099_Qual_Plan.pdf](#)

[PCN_JAON-04IGFH099_Pre and Post Change_Summary.pdf](#)

Please contact your local [Microchip sales office](#) with questions or concerns regarding this notification.

Terms and Conditions:

If you wish to receive Microchip PCNs via email please register for our PCN email service at our [PCN home page](#) select register then fill in the required fields. You will find instructions about registering for Microchips PCN email service in the [PCN FAQ](#) section.

If you wish to change your PCN profile, including opt out, please go to the [PCN home page](#) select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.

Affected Catalog Part Numbers (CPN)

MCP1407-E/SN
MCP1407T-E/SN
TC1410COA
TC1410EOA
TC1410EOA713
TC1410COA713
TC1411COA
TC1411VOA
TC1411EOA
TC1411EOA713
TC1411COA713
TC1411VOA713
TC1411NCOA
TC1411NVOA
TC1411NEOA
TC1411NEOA713
TC1411NCOA713
TC1411NVOA713
TC1412NCOA
TC1412NEOA
TC1412NEOA713
TC1412NCOA713
TC1413NCOA
TC1413NEOA
TC1413NEOA713
TC1413NCOA713
TC4420COA
TC4420VOA
TC4420EOA
TC4420EOA713
TC4420COA713
TC4420VOA713
TC4429COA
TC4429VOA
TC4429EOA
TC4429EOAAAC
TC4429EOA713
TC4429COA713
TC4429VOA713

CCB 4542

Pre and Post Change Summary

PCN # JAON-04IGFH099



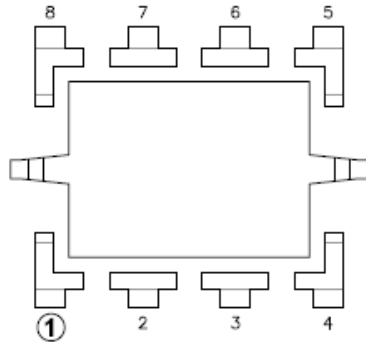
A Leading Provider of Smart, Connected and Secure Embedded Control Solutions



SMART | CONNECTED | SECURE

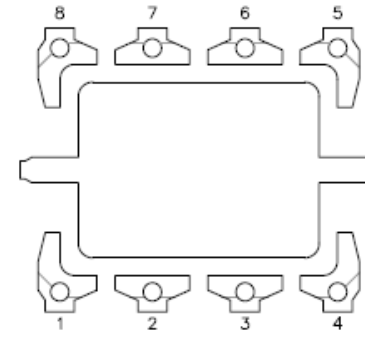
Lead frame Comparison

Pre Change

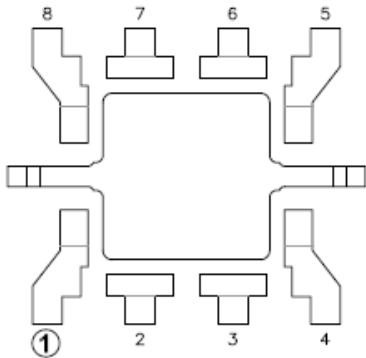


LF STRIP DENSITY: x140
LF PAD SIZE: 95x130 mils
LEAD LOCK: NO

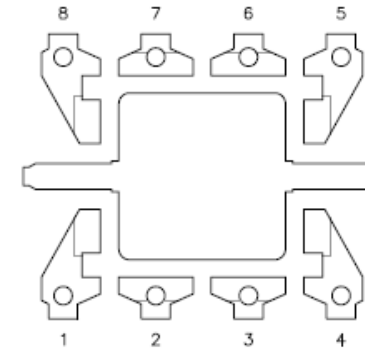
Post Change



LF STRIP DENSITY: x320
LF PAD SIZE: 95x130 mils
LEAD LOCK: YES



LF STRIP DENSITY: x140
LF PAD SIZE: 90x90 mils
LEAD LOCK: NO



LF STRIP DENSITY: x320
LF PAD SIZE: 90x90 mils
LEAD LOCK: YES



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QUALIFICATION PLAN SUMMARY

PCN #: JAON-04IGFH099

Date

January 21, 2021

Qualification of a new lead frame design for selected products available in 8L SOIC package using 8900NC die attach and gold (Au) bond wire material assembled at MMT assembly site.

Purpose: Qualification of a new lead frame design for selected products available in 8L SOIC package using 8900NC die attach and gold (Au) bond wire material assembled at MMT assembly site.

CCB No.: 4542

<u>Misc.</u>	Assembly site	MMT
	BD Number	BDM-002817/A
	MP Code (MPC)	Y2AC2BC2XA00
	Part Number (CPN)	TC1412NEOA
	MSL information	MSL-1/260C
	Assembly Shipping Media (T/R, Tube/Tray)	Tube
	Base Quantity Multiple (BQM)	100
	Reliability Site	MTAI
<u>Lead-Frame</u>	Paddle size	95x130 mils
	Material	CDA194
	DAP Surface Prep	Bare Cu
	Treatment	BOT
	Process	Etched
	Lead-lock	Yes
	Part Number	10100842
	Lead Plating	Matte Tin
	Strip Size	239.0x70.0mm
	Strip Density	320 pads/strip
<u>Bond Wire</u>	Material	Au
<u>Die Attach</u>	Part Number	8900NC
	Conductive	Yes
<u>MC</u>	Part Number	G600V
<u>PKG</u>	PKG Type	SOIC
	Pin/Ball Count	8
	PKG width/size	150 mils

Test Name	Conditions	Sample Size	Min. Qty of Spares per Lot (should be properly marked)	Qty of Lots	Total Units	Fail Accept Qty	Est. Dur. Days	Test Site	Special Instructions
Standard Pb-free Solderability	J-STD-002 ; Perform 8 hour steam aging for Matte tin finish and 1 hour steam aging for NiPdAu finish prior to testing. Standard Pb-free: Matte tin/ NiPdAu finish, SAC solder, wetting temp 245°C for both SMD & through hole packages.	22	5	1	27	> 95% lead coverage	5		Standard Pb-free solderability is the requirement. SnPb solderability (backward solderability- SMD reflow soldering) is required for any plating related changes and highly recommended for other package BOM changes.
Wire Bond Pull - WBP	Mil. Std. 883-2011	5	0	3	15	0 fails after TC	5	MMT/MTAI	30 bonds from a minimum of 5 devices.
Wire Bond Shear - WBS	CDF-AEC-Q100-001	5	0	3	15	0	5	MMT/MTAI	30 bonds from a minimum of 5 devices.
Wire Sweep		5	0	3	15	0		MMT	Required for any reduction in wire bond thickness.
Physical Dimensions	Measure per JESD22 B100 and B108	10	0	3	30	0	5	MMT	
External Visual	Mil. Std. 883-2009/2010	All devices prior to submission for qualification testing	0	3	ALL	0	5	MMT/ MTAI	
Preconditioning - Required for surface mount devices	+150°C Bake for 24 hours, moisture loading requirements per MSL level + 3X reflow at peak reflow temperature per Jedec-STD-020E for package type; Electrical test pre and post stress at +25°C. MSL1/260C	231	15	3	738	0	15	MTAI	Spares should be properly identified. 77 parts from each lot to be used for HAST, Autoclave, Temp Cycle test.

Test Name	Conditions	Sample Size	Min. Qty of Spares per Lot (should be properly marked)	Qty of Lots	Total Units	Fail Accept Qty	Est. Dur. Days	Test Site	Special Instructions
HAST	+130°C/85% RH for 96 hours. Electrical test pre and post stress at +25°C and hot temp.	77	5	3	246	0	10	MTAI	Spares should be properly identified. Use the parts which have gone through Pre-conditioning.
Unbiased HAST	+130°C/85% RH for 96 hrs. Electrical test pre and post stress at +25°C.	77	5	3	246	0	10	MTAI	Spares should be properly identified. Use the parts which have gone through Pre-conditioning.
Temp Cycle	-65°C to +150°C for 500 cycles. Electrical test pre and post stress at hot temp; 3 gram force WBP, on 5 devices from 1 lot, test following Temp Cycle stress.	77	5	3	246	0	15	MTAI	Spares should be properly identified. Use the parts which have gone through Pre-conditioning.